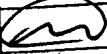
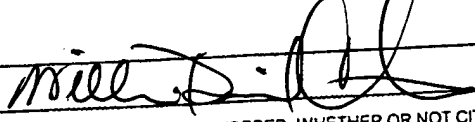


FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.0950V2C1	APPLICATION NO. <del>Unknown</del> 10/679,822
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Agarwal, et al.	
		FILING DATE <del>Herein</del> 10/6/2003	GROUP 2823

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	4,761,386	8/2/88	Buynoski			
	4,823,182	4/18/89	Okumura			
	4,884,123	11/28/89	Dixit, et al.			
	4,895,770	1/23/90	Schintlmeister, et al.			
	4,920,071	4/24/90	Thomas			
	5,225,771	7/6/93	Leedy			
	5,248,903	9/28/93	Heim			
	5,298,333	3/29/94	Maixner, et al.			
	5,364,803	11/15/94	Lur, et al.			
	5,391,516	2/21/95	Wojnarowski, et al.			
	5,441,904	8/15/95	Kim, et al.			
	5,486,492	1/23/96	Yamamoto, et al.			
	5,506,499	4/9/96	Puar			
	5,541,427	7/30/96	Chappell, et al.			
	5,593,903	1/14/97	Beckenbaugh, et al.			
	5,668,394	9/16/97	Lur, et al.			
	5,684,304	11/4/97	Smears			
	5,693,377	12/2/97	Westmoreland, et al.			
	5,720,098	2/24/98	Kister			
	5,742,174	4/21/98	Kister, et al.			
	5,837,598	11/17/98	Aronowitz, et al.			
	5,851,680	12/22/98	Heau			
	5,920,081	7/6/99	Chen, et al.			
	5,962,867	10/5/99	Liu			
	5,968,594	10/19/99	Hu, et al.			
	5,994,716	11/30/99	Ikeya, et al.			
	6,028,360	2/22/00	Nakamura, et al.			

EXAMINER 	DATE CONSIDERED 3/2/2005
*EXAMINER: INITIAL IF CITATION CONSIDERED. WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MICRON.095DV2C1	APPLICATION NO. (Unknown) 10/679,822
	APPLICANT Agarwal, et al.	
	FILING DATE Herewith 10/6/2003	GROUP 2823

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	6,017,818	1/25/00	Lu			
	6,069,482	5/30/00	Hilton			
	6,133,582	10/17/00	Osann, Jr., et al.			
	6,200,649	3/13/01	Dearnaley			

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	EP 0854 505 A2	7/22/98	Europe				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	Baker, et al. "Combined X-Ray Photoelectron/auger Electron Spectroscopy/Glaning Angle X-Ray diffraction/Extended X-Ray Absorbion Fine Structure Investigation of TiBxNy Coatings". J. Vac. Sci. Technol., A 15(2), pp. 284-291, March/April 1997
	Sade, et al., "Characterization of TiB2/TiSi2 Bilayer Structure Deposited By Sputtering", Mat. Res. Soc. Smp. Proc., Vol. 402, pp. 131-136, 1996

H:\DOCS\KJLKJL-2351.DOC  
100103

EXAMINER	DATE CONSIDERED 3/2/2005
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 608; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	